Search Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/784,950	KAMIYA ET AL.	
Examiner	Art Unit	
Patrick H. Mackey	3651	

Patrick H. Mackey

	SEAR	CHED	
Class	Subclass	Date	Examiner
271	220		
	221		
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270	58.11		
	58.12		
	58.16		
	58.17	7/15/2005	РНМ
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Plus Search		7/15/2005	РНМ
Text Search		7/15/2005	РНМ
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